

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"5326709".pn. or "6788993".pn.	US-PGPUB; USPAT	OR	ON	2005/02/23 10:04
L2	4	"6594611"	US-PGPUB; USPAT	OR	ON	2005/02/23 10:07
L3	1	"6788993"	US-PGPUB; USPAT	OR	ON	2005/02/23 10:07
L4	1554	702/118,119,117,81,82,87,84. ccls.	US-PGPUB; USPAT	OR	ON	2005/02/23 10:07
L5	1530	700/224,226,116,95,109,115,117. ccls.	US-PGPUB; USPAT	OR	ON	2005/02/23 10:08
L6	2981	4 or 5	US-PGPUB; USPAT	OR	ON	2005/02/23 10:08

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	49	("5915231" "6049624" "6067507" "6208947" "6226394" "6226394" "6363329" "6400840" "6588854" "6594611" "5907492" "6363295" "6553276" "5859803" "5426072" "5844803" "5856923" "5927512" "6100486" "6122563" "6147316" "6180527" "6307171" "6350959" "6365860" "6365861" "6373011" "6427092" "6437271" "6504123" "6703573" "4387946" "6344401" "5497381" "6307755" "5532612" "6060895" "5972798" "6608385" "6641430" "6676438" "6750136" "5726920" "4343878" "4442188" "5898186" "5976899" "5994915" "6072574" "6091249").pn.	US-PGPUB; USPAT	OR	ON	2005/02/23 13:55

10600148_CLS.txt
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10600148 on February 23, 2005

Original Classifications

11 209/573
7 700/121
4 382/145
4 702/118
2 324/760
2 430/5
2 439/482

Cross-Reference Classifications

14 257/E23.179
13 324/765
11 209/571
9 324/158.1
9 700/116
5 438/14
5 700/224
5 702/187
5 702/82
4 700/226
4 702/117
3 700/108
3 700/109
2 209/583
2 257/E21.525
2 257/E25.013
2 324/704
2 324/754
2 430/22
2 430/311
2 430/394
2 430/396
2 438/17
2 438/691
2 438/692
2 700/117
2 700/215
2 702/118

Combined Classifications

14 257/E23.179
14 324/765
12 209/573
11 209/571
9 324/158.1
9 700/116
8 700/121
6 438/14
6 702/118
5 382/145
5 700/224
5 702/187
5 702/82
4 700/226
4 702/117
3 700/108
3 700/109
2 209/583
2 257/E21.525

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2 257/E25.013
2 324/704
2 324/754
2 324/760
2 430/22
2 430/311
2 430/394
2 430/396
2 430/5
2 438/17
2 438/691
2 438/692
2 439/482
2 700/117
2 700/215

Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10600148 on February 23, 2005

- 14 257/E23.179 (0 OR, 14 XR)
 Class 257 : ACTIVE SOLID-STATE DEVICES
 257/E23.176 ...For flat cards, e.g., credit cards (EPO)
 257/E23.179 .Marks applied to semiconductor devices or
 parts, e.g., registration marks, test patterns, alignment
 structures, wafer maps (EPO)
- 14 324/765 (1 OR, 13 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/765 ..Test of semiconductor device
- 12 209/573 (11 OR, 1 XR)
 Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
 209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
 APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
 SORTING, ETC.) FOR SORTING ANY ITEMS
 209/552 .Condition responsive means controls separating
 means
 209/571 ..Electrical test sensing property of item
 209/573 ...Electrical component tested
- 11 209/571 (0 OR, 11 XR)
 Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
 209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
 APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
 SORTING, ETC.) FOR SORTING ANY ITEMS
 209/552 .Condition responsive means controls separating
 means
 209/571 ..Electrical test sensing property of item
- 9 324/158.1 (0 OR, 9 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/158.1 MISCELLANEOUS
- 9 700/116 (0 OR, 9 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 700/95 .Product assembly or manufacturing
 700/115 ..Product tracking (e.g., having product or
 carrier identification)
 700/116 ...Having identification controlled
 manufacturing operation
- 8 700/121 (7 OR, 1 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 700/95 .Product assembly or manufacturing
 700/117 ..Particular manufactured product or operation
 700/121 ...Integrated circuit production or

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semiconductor fabrication

- 6 438/14 (1 OR, 5 XR)
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/14 WITH MEASURING OR TESTING
- 6 702/118 (4 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/108 TESTING SYSTEM
702/117 .Of circuit
702/118 ..Testing multiple circuits
- 5 382/145 (4 OR, 1 XR)
Class 382 : IMAGE ANALYSIS
382/100 APPLICATIONS
382/141 .Manufacturing or product inspection
382/145 ..Inspection of semiconductor device or printed
circuit board
- 5 700/224 (0 OR, 5 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/213 .Article handling
700/219 ..Associating or disassociating plural articles
700/223 ...Collating or sorting
700/224Having an identification code
- 5 702/187 (0 OR, 5 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/127 MEASUREMENT SYSTEM
702/187 .History logging or time stamping
- 5 702/82 (0 OR, 5 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/81 .Quality evaluation
702/82 ..Having judging means (e.g., accept/reject)
- 4 700/226 (0 OR, 4 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/213 .Article handling
700/225 ..Having an identification code
700/226 ...Identification code determines article
destination
- 4 702/117 (0 OR, 4 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/108 TESTING SYSTEM
702/117 .Of circuit
- 3 700/108 (0 OR, 3 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS

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700/95 .Product assembly or manufacturing
700/108 ..Performance monitoring

3 700/109 (0 OR, 3 XR)
Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
SPECIFIC APPLICATIONS
700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
700/95 .Product assembly or manufacturing
700/108 ..Performance monitoring
700/109 ...Quality control

2 209/583 (0 OR, 2 XR)
Class 209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
209/509 SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING, ETC.) FOR SORTING ANY ITEMS
209/552 .Condition responsive means controls separating
means
209/576 ..Sensing radiant energy reflected, absorbed,
emitted, or obstructed by item or adjunct thereof
209/577 ...Infrared, visible light, or ultraviolet
209/583Reading indicia

2 257/E21.525 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E21.515Involving use of mechanical auxiliary part
without use of alloying or soldering process, e.g.,
pressure contacts (EPO)
257/E21.521 .Testing or measuring during manufacture or
treatment or reliability measurement, i.e., testing of
parts followed by no processing which modifies parts as
such (EPO)
257/E21.525 ..Procedures, i.e., sequence of activities
consisting of plurality of measurement and correction,
marking or sorting steps (EPO)

2 257/E25.013 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E25.001 ASSEMBLIES CONSISTING OF PLURALITY OF
INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES
(EPO)
257/E25.002 .All devices being of same type, e.g.,
assemblies of rectifier diodes (EPO)
257/E25.003 ..Devices not having separate containers (EPO)
257/E25.01 ...Device consisting of plurality of
semiconductor or other solid state devices or components
formed in or on common substrate, e.g., integrated
circuit device (EPO)
257/E25.013Stacked arrangements of devices (EPO)

2 324/704 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE
RELATIONSHIPS
324/649 .Lumped type parameters
324/691 ..Using resistance or conductance measurement

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324/704 ...With ratio determination

2 324/754 (0 OR, 2 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/754 ..With probe elements

2 324/760 (2 OR, 0 XR)
 Class 324 : ELECTRICITY: MEASURING AND TESTING
 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
 ELECTRIC COMPONENTS
 324/537 .Of individual circuit component or element
 324/754 ..With probe elements
 324/760 ...With temperature control

2 430/22 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/22 REGISTRATION OR LAYOUT PROCESS OTHER THAN COLOR
 PROOFING

2 430/311 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/269 IMAGING AFFECTING PHYSICAL PROPERTY OF
 RADIATION SENSITIVE MATERIAL, OR PRODUCING NONPLANAR OR
 PRINTING SURFACE - PROCESS, COMPOSITION, OR PRODUCT
 430/311 .Making electrical device

2 430/394 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/394 PLURAL EXPOSURE STEPS

2 430/396 (0 OR, 2 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/396 EFFECTING FRONTAL RADIATION MODIFICATION DURING
 EXPOSURE, E.G., SCREENING, MASKING, STENCILING, ETC.

2 430/5 (2 OR, 0 XR)
 Class 430 : RADIATION IMAGERY CHEMISTRY: PROCESS,
 COMPOSITION, OR PRODUCT THEREOF
 430/4 RADIATION MODIFYING PRODUCT OR PROCESS OF
 MAKING
 430/5 .Radiation mask

2 438/17 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 438/14 WITH MEASURING OR TESTING
 438/17 .Electrical characteristic sensed

2 438/691 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 438/689 CHEMICAL ETCHING
 438/690 .Combined with the removal of material by
 nonchemical means (e.g., ablating, abrading, etc.)
 438/691 ..Combined mechanical and chemical material
 removal

- 2 438/692 (0 OR, 2 XR)
 Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
 - 438/689 CHEMICAL ETCHING
 - 438/690 .Combined with the removal of material by
 nonchemical means (e.g., ablating, abrading, etc.)
 - 438/691 ..Combined mechanical and chemical material
 removal
 - 438/692 ...Simultaneous (e.g., chemical-mechanical
 polishing, etc.)

- 2 439/482 (2 OR, 0 XR)
 Class 439 : ELECTRICAL CONNECTORS
 - 439/476.1 INCLUDING HANDLE OR DISTINCT MANIPULATING MEANS
 - 439/481 .Randomly manipulated implement
 - 439/482 ..Test probe

- 2 700/117 (0 OR, 2 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 - 700/95 .Product assembly or manufacturing
 - 700/117 ..Particular manufactured product or operation

- 2 700/215 (0 OR, 2 XR)
 Class 700 : DATA PROCESSING: GENERIC CONTROL SYSTEMS OR
 SPECIFIC APPLICATIONS
 - 700/90 SPECIFIC APPLICATION, APPARATUS OR PROCESS
 - 700/213 .Article handling
 - 700/214 ..Article storing, retrieval, or arrangement
 (e.g., warehousing, automated library)
 - 700/215 ...Having an identification code

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5915231 99
6049624 99
6067507 99
6208947 99
6226394 99
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6400840 99
6588854 99
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5907492 94
6363295 94
6553276 94
5859803 91
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PLUS Search Results for S/N 10600148, Searched February 23, 2005

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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Day : Wednesday

Date: 2/23/2005

Time: 15:48:15

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Content Information for 10/600148

Search Another: Application# or Patent#

PCT / / or PG PUBS #

Attorney Docket #

Bar Code #

Appln Info	Contents	Petition Info	Atty/Agent Info	Continuity Data	Foreign Data
Date	Status	Code	Description		
02/23/2005		P574	PARALEGAL TD ACCEPTED		
04/19/2004		DIST	TERMINAL DISCLAIMER FILED		
02/04/2005		RCAP	REFERENCE CAPTURE ON IDS		
02/04/2005		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED		
02/18/2005		FWDX	DATE FORWARDED TO EXAMINER		
02/04/2005	71	RCEX	REQUEST FOR CONTINUED EXAMINATION (RCE)		
02/18/2005		ABN9	DISPOSAL FOR A RCE/CPA/129 (EXPRESS ABANDONM		
02/15/2005	91	P006	RECORD PETITION DECISION OF GRANTED TO WITH		
02/04/2005		PET.	PETITION ENTERED		
02/04/2005		WPET	WORKFLOW INCOMING PETITION IFW		
02/04/2005		BRCE	WORKFLOW - REQUEST FOR RCE - BEGIN		
09/24/2004		EIDC	EXPORT TO INITIAL DATA CAPTURE		
12/06/2004	94	IFEE	ISSUE FEE PAYMENT RECORDED		
09/16/2004	92	MN/=.	MAIL NOTICE OF ALLOWANCE		
09/15/2004		IREV	ISSUE REVISION COMPLETED		
09/15/2004	90	N/=.	NOTICE OF ALLOWANCE DATA VERIFICATION COMI		
09/15/2004	89	CNTA	NOTICE OF ALLOWABILITY		
07/30/2004		RCAP	REFERENCE CAPTURE ON IDS		
07/30/2004		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILED		
09/10/2004		FWDX	DATE FORWARDED TO EXAMINER		
07/30/2004	71	RCEX	REQUEST FOR CONTINUED EXAMINATION (RCE)		
09/10/2004		ABN9	DISPOSAL FOR A RCE/CPA/129 (EXPRESS ABANDONM		
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07/30/2004		WAMD	WORKFLOW INCOMING AMENDMENT IFW		
07/30/2004		BRCE	WORKFLOW - REQUEST FOR RCE - BEGIN		

07/07/2004		SENT	WORKFLOW - FILE SENT TO CONTRACTOR
06/18/2004	92	MN/=.	MAIL NOTICE OF ALLOWANCE
06/16/2004		IREV	ISSUE REVISION COMPLETED
06/14/2004	90	N/=.	NOTICE OF ALLOWANCE DATA VERIFICATION COM
06/14/2004	89	CNTA	NOTICE OF ALLOWABILITY
04/27/2004		FWDX	DATE FORWARDED TO EXAMINER
04/19/2004	71	A...	RESPONSE AFTER NON-FINAL ACTION
04/19/2004		WAMD	WORKFLOW INCOMING AMENDMENT IFW
01/14/2004	41	MCTNF	MAIL NON-FINAL REJECTION
01/07/2004	40	CTNF	NON-FINAL REJECTION
12/23/2003		TSSA	IFW AMENDED CASE PROCESSING COMPLETE
12/01/2003		A.PE	PRELIMINARY AMENDMENT
06/19/2003		RCAP	REFERENCE CAPTURE ON IDS
06/19/2003		M844	INFORMATION DISCLOSURE STATEMENT (IDS) FILEI
12/23/2003	30	DOCK	CASE DOCKETED TO EXAMINER IN GAU
12/01/2003		A.PE	PRELIMINARY AMENDMENT
10/27/2003	20	WROIPE	APPLICATION RETURN FROM OIPE
10/27/2003		COMP	APPLICATION IS NOW COMPLETE
10/27/2003		W/OA	PRE-EXAM OFFICE ACTION WITHDRAWN
10/27/2003	18	ROIPE	APPLICATION RETURN TO OIPE
10/27/2003	20	WROIPE	APPLICATION RETURN FROM OIPE
10/27/2003		COMP	APPLICATION IS NOW COMPLETE
10/27/2003		W/OA	PRE-EXAM OFFICE ACTION WITHDRAWN
10/27/2003	18	ROIPE	APPLICATION RETURN TO OIPE
10/27/2003	20	WROIPE	APPLICATION RETURN FROM OIPE
10/27/2003		COMP	APPLICATION IS NOW COMPLETE
10/27/2003		W/OA	PRE-EXAM OFFICE ACTION WITHDRAWN
10/27/2003	18	ROIPE	APPLICATION RETURN TO OIPE
10/24/2003	20	WROIPE	APPLICATION RETURN FROM OIPE
10/27/2003		COMP	APPLICATION IS NOW COMPLETE
10/27/2003		W/OA	PRE-EXAM OFFICE ACTION WITHDRAWN
10/24/2003	18	ROIPE	APPLICATION RETURN TO OIPE
10/24/2003	20	WROIPE	APPLICATION RETURN FROM OIPE
10/27/2003		COMP	APPLICATION IS NOW COMPLETE
10/24/2003		W/OA	PRE-EXAM OFFICE ACTION WITHDRAWN
10/24/2003	18	ROIPE	APPLICATION RETURN TO OIPE
10/24/2003	20	OIPE	APPLICATION DISPATCHED FROM OIPE

10/24/2003		COMP	APPLICATION IS NOW COMPLETE
08/25/2003		CLSS	CASE CLASSIFIED BY L&R
08/25/2003		L194	CLEARED BY OIPE CSR
08/15/2003		SCAN	IFW SCAN & PACR AUTO SECURITY REVIEW
06/19/2003	19	IEXX	INITIAL EXAM TEAM NN

AppIn Info	Contents	Petition Info	Atty/Agent Info	Continuity Data	Foreign Data
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